09/845,562

L Number	Hits	Search Text	DB	Time stamp
1	3972123	integrated circuit with dual mode test access port\$1	USPAT;	2004/02/17 10:34
-		The state of the state state and the state of the state o	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
2	3009849	data register\$1	USPAT;	2004/02/17 10:35
-	3003013	data register#1	US-PGPUB;	2004/02/17 10.55
	f		EPO; JPO;	
	į		DERWENT;	
			IBM_TDB	
3	1243909	(integrated circuit with dual mode test access port\$1) and ( data	USPAT;	2004/02/17 10:26
,	1243909	register\$1)	US-PGPUB;	2004/02/17 10:36
		register#1)		
	1		EPO; JPO;	
	[		DERWENT;	
1	2405020	intellectual avenues.	IBM_TDB	2004/02/47 40 27
4	2495028	intellectual property core\$1	USPAT;	2004/02/17 10:37
			US-PGPUB;	
	ł		EPO; JPO;	
			DERWENT;	
_			IBM_TDB	
5	2078445	externally accessible scan path\$1	USPAT;	2004/02/17 10:37
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
6	431880	(intellectual property core\$1) and (externally accessible scan	USPAT;	2004/02/17 10:37
		path\$1)	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
7	169853	((intellectual property core\$1) and (externally accessible scan	USPAT;	2004/02/17 10:40
		path\$1)) and ((integrated circuit with dual mode test access	US-PGPUB;	
		port\$1) and ( data register\$1))	EPO; JPO;	
			DERWENT;	
			IBM_TDB	
8	46	"IEEE 1149.1 TAP"	USPAT;	2004/02/17 10:41
			US-PGPUB;	, ,
İ			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
9	33	(((intellectual property core\$1) and (externally accessible scan	USPAT;	2004/02/17 10:42
		path\$1)) and ((integrated circuit with dual mode test access	US-PGPUB;	
		port\$1) and ( data register\$1))) and "IEEE 1149.1 TAP"	EPO; JPO;	
	ļ		DERWENT;	
]			IBM_TDB	
11	5470459	enabl\$3 signal\$1	USPAT;	2004/02/17 10:43
			US-PGPUB;	
			EPO; JPO;	
	İ		DERWENT;	
			IBM_TDB	
12	3709152	disabl\$3 signal\$1	USPAT;	2004/02/17 10:43
	1		US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
13	3681902	(enabl\$3 signal\$1) and (disabl\$3 signal\$1)	USPAT;	2004/02/17 10:45
15	3001902	(Chasiya aigilaly) and (diadbiya aigilaly)	US-PGPUB;	2007/02/17 10:45
	j		EPO; JPO;	
			DERWENT;	
	İ			
	l,	L	IBM_TDB	

14	33	((((intellectual property core\$1) and (externally accessible scan	USPAT;	2004/02/17 10:48
17	33	path\$1)) and ((integrated circuit with dual mode test access	US-PGPUB;	2004/02/17 10.46
		port\$1) and ((integrated circuit with data mode test access port\$1) and ( data register\$1))) and "IEEE 1149.1 TAP") and	EPO; JPO;	
		((enabl\$3 signal\$1) and (disabl\$3 signal\$1))	DERWENT;	
		((Guanipo siguaipo) aud (disanipo siguaipo))	IBM_TDB	
10	1074021	TAP test interface		2004/02/17 10:40
15	1974031	TAP test interrace	USPAT;	2004/02/17 10:49
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	,
_			IBM_TDB	
16	2214968	alternate test interface	USPAT;	2004/02/17 10:49
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
17	1863922	(TAP test interface) and (alternate test interface)	USPAT;	2004/02/17 10:50
		(**************************************	US-PGPUB;	
			EPO; JPO;	
	1		DERWENT;	
10	22	(((((intellectual property seret1) and (sytemally assessible seen	IBM_TDB	2004/02/17 10:50
18	33		USPAT;	2004/02/17 10:50
		path\$1)) and ((integrated circuit with dual mode test access	US-PGPUB;	
		port\$1) and ( data register\$1))) and "IEEE 1149.1 TAP") and	EPO; JPO;	
		((enabl\$3 signal\$1) and (disabl\$3 signal\$1))) and ((TAP test	DERWENT;	
		interface) and (alternate test interface))	IBM_TDB	
19	3163057	scan data register\$1	USPAT;	2004/02/17 10:50
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
20	1123817	boundary scan register\$1	USPAT;	2004/02/17 10:50
		Journal   Jour	US-PGPUB;	200 1, 02, 17 10:00
		•	EPO; JPO;	
			DERWENT;	
			IBM_TDB	
21	684272	bypass register\$1	USPAT;	2004/02/17 10:50
21	007272	Dypass register \$1		2007/02/17 10.50
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
22	004404	// / // // // // // // // // // // // /	IBM_TDB	2004/00//
22	904426	(boundary scan register\$1) and (scan data register\$1)	USPAT;	2004/02/17 10:52
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
23	542391	(bypass register\$1) and ((boundary scan register\$1) and (scan	USPAT;	2004/02/17 10:52
		data register\$1))	US-PGPUB;	_
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
24	881375	instruction register\$1	USPAT;	2004/02/17 10:54
24			US-PGPUB;	250 1,02,17 10.54
			EPO; JPO;	
				1
			DERWENT;	
25	F27422	//h.maga_masistantd\	IBM_TDB	2004/02/47 40 77
25	537439	((bypass register\$1) and ((boundary scan register\$1) and (scan	USPAT;	2004/02/17 10:55
		data register\$1))) and (instruction register\$1)	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
	1	I	IBM_TDB	1

26	24	(((bypass register\$1) and ((boundary scan register\$1) and (scan	USPAT;	2004/02/17 10:55
		data register\$1))) and (instruction register\$1)) and	US-PGPUB;	
		((((((intellectual property core\$1) and (externally accessible scan	EPO; JPO;	
		path\$1)) and ((integrated circuit with dual mode test access	DERWENT;	
		port\$1) and ( data register\$1))) and "IEEE 1149.1 TAP") and ((enabl\$3 signal\$1) and (disabl\$3 signal\$1))) and ((TAP test	IBM_TDB	
		interface) and (alternate test interface)))		
27	5048293	first protocol	USPAT;	2004/02/17 10:55
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
20	4740224	accord protect	IBM_TDB	2004/02/47 40-55
28	4740324	second protocol	USPAT; US-PGPUB;	2004/02/17 10:55
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
29	4205536	(first protocol) and (second protocol)	USPAT;	2004/02/17 10:57
			US-PGPUB;	
			EPO; JPO; DERWENT;	
			IBM_TDB	
30	24	((((bypass register\$1) and ((boundary scan register\$1) and (scan	USPAT;	2004/02/17 10:59
		data register\$1))) and (instruction register\$1)) and	US-PGPUB;	,,
	İ	((((((intellectual property core\$1) and (externally accessible scan	EPO; JPO;	
		path\$1)) and ((integrated circuit with dual mode test access	DERWENT;	
		port\$1) and (data register\$1))) and "IEEE 1149.1 TAP") and	IBM_TDB	
		((enabl\$3 signal\$1) and (disabl\$3 signal\$1))) and ((TAP test interface) and (alternate test interface)))) and ((first protocol) and		
		(second protocol))		